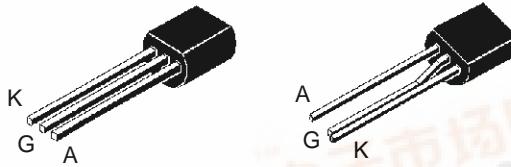


## SENSITIVE GATE SCR

### FEATURES

- $I_T(\text{RMS}) = 0.8\text{A}$
- $V_{\text{DRM}} = 100\text{V}$  to  $400\text{V}$
- Low  $I_{\text{GT}} < 1\mu\text{A}$  max to  $< 200\mu\text{A}$



TO92  
(Plastic)

P01xxxA

RD26  
(Plastic)

P01xxxB

### DESCRIPTION

The P01xxxA/B series of SCRs uses a high performance planar PNPN technology. These parts are intended for general purpose applications where low gate sensitivity is required.

### ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
$I_T(\text{RMS})$	RMS on-state current ( $180^\circ$ conduction angle)	0.8	A
$I_T(\text{AV})$	Mean on-state current ( $180^\circ$ conduction angle)	0.5	A
$I_{TSM}$	Non repetitive surge peak on-state current ( $T_j$ initial = $25^\circ\text{C}$ )	tp = 8.3 ms	A
		tp = 10 ms	
$I^2t$	$I^2t$ Value for fusing	0.24	$\text{A}^2\text{s}$
$dI/dt$	Critical rate of rise of on-state current $I_G = 10 \text{ mA}$ $dI/dt = 0.1 \text{ A}/\mu\text{s}$ .	30	$\text{A}/\mu\text{s}$
$T_{\text{stg}}$ $T_j$	Storage and operating junction temperature range	- 40, + 150 - 40, + 125	$^\circ\text{C}$
TI	Maximum lead temperature for soldering during 10s at 2mm from case	260	$^\circ\text{C}$

Symbol	Parameter	Voltage				Unit
		A	B	C	D	
$V_{\text{DRM}}$ $V_{\text{RRM}}$	Repetitive peak off-state voltage $T_j = 125^\circ\text{C}$ $R_{\text{GK}} = 1\text{K}\Omega$	100	200	300	400	V

[查询"P0102AA1AA3"供应商](#)

P01xxxA/B

### THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R <sub>th(j-a)</sub>	Junction to ambient	150	°C/W
R <sub>th(j-l)</sub>	Junction to leads for DC	80	°C/W

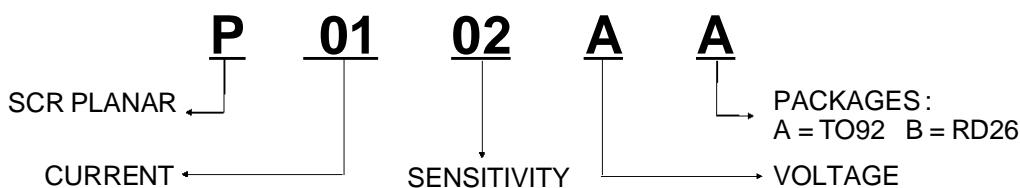
### GATE CHARACTERISTICS (maximum values)

P<sub>G(AV)</sub>= 0.1 W P<sub>GM</sub> = 2 W (tp = 20 μs) I<sub>GM</sub> = 1 A (tp = 20 μs)

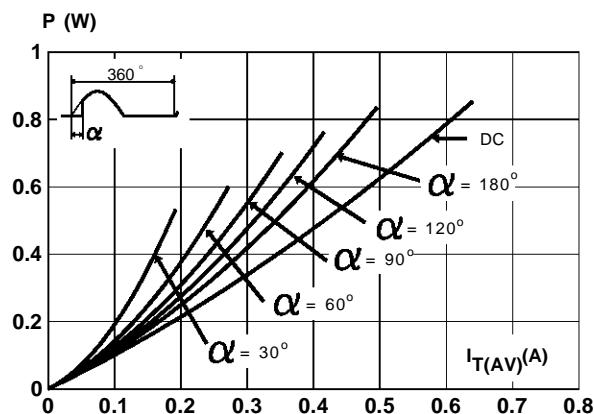
### ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions	Sensitivity					Unit		
		02	09	11	15	18			
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MIN			4	15	0.5	μA
			MAX	200	1	25	50	5	
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MAX	0.8				V	
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> R <sub>L</sub> =3.3kΩ R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MIN	0.1				V	
V <sub>RGM</sub>	I <sub>RG</sub> =10μA	T <sub>j</sub> = 25°C	MIN	8				V	
t <sub>gd</sub>	V <sub>D</sub> =V <sub>DRM</sub> I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> dI <sub>G</sub> /dt = 0.1A/μs I <sub>G</sub> = 10mA	T <sub>j</sub> = 25°C	TYP	0.5				μs	
I <sub>H</sub>	I <sub>T</sub> = 50mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	5				mA	
I <sub>L</sub>	I <sub>G</sub> =1mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	6				mA	
V <sub>TM</sub>	I <sub>TM</sub> = 1.6A tp= 380μs	T <sub>j</sub> = 25°C	MAX	1.93				V	
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>D</sub> = V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ V <sub>R</sub> = V <sub>RRM</sub>	T <sub>j</sub> = 25°C	MAX	1				μA	
		T <sub>j</sub> = 125°C	MAX	100				μA	
dV/dt	V <sub>D</sub> =67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MIN	25	25	50	100	30	V/μs
t <sub>q</sub>	I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> V <sub>R</sub> =35V dI/dt=10A/μs tp=100μs dV/dt=10V/μs V <sub>D</sub> = 67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MAX	200				μs	

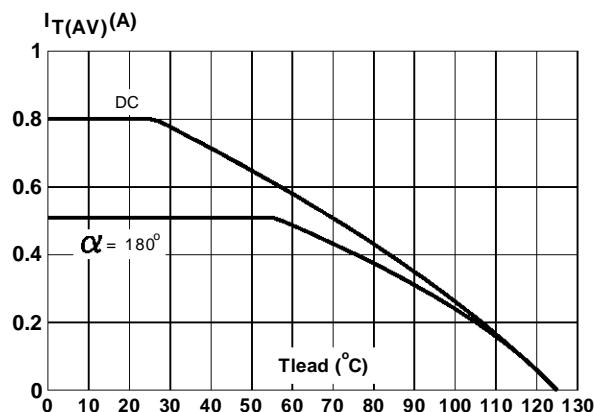
### ORDERING INFORMATION



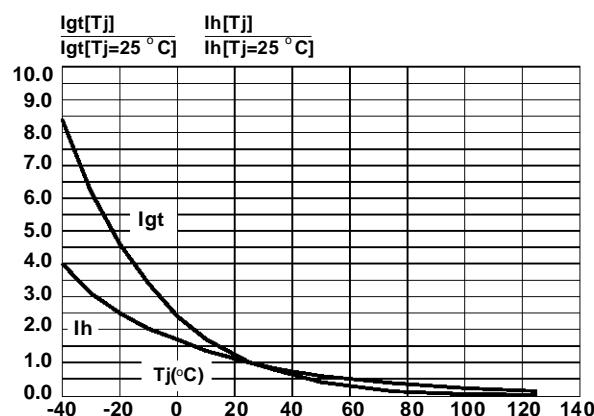
**Fig.1** : Maximum average power dissipation versus average on-state current.



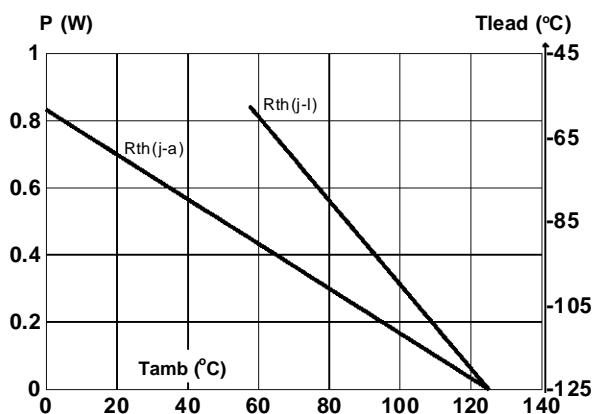
**Fig.3** : Average on-state current versus lead temperature.



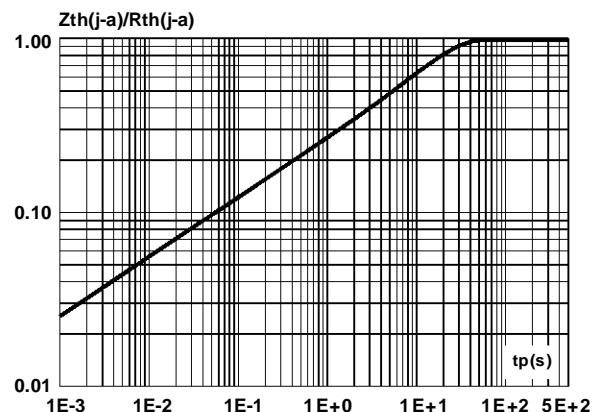
**Fig.5** : Relative variation of gate trigger current and holding current versus junction temperature.



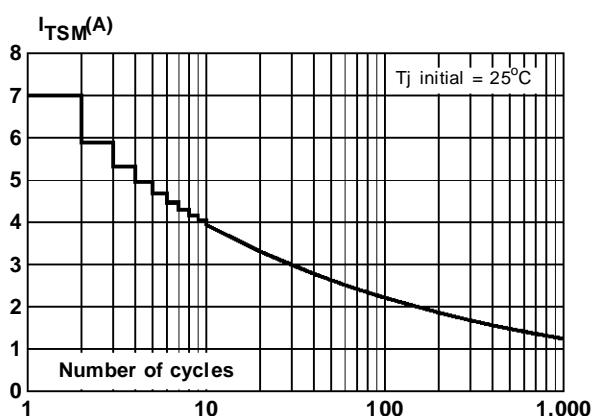
**Fig.2** : Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tlead).



**Fig.4** : Relative variation of thermal impedance junction to ambient versus pulse duration.



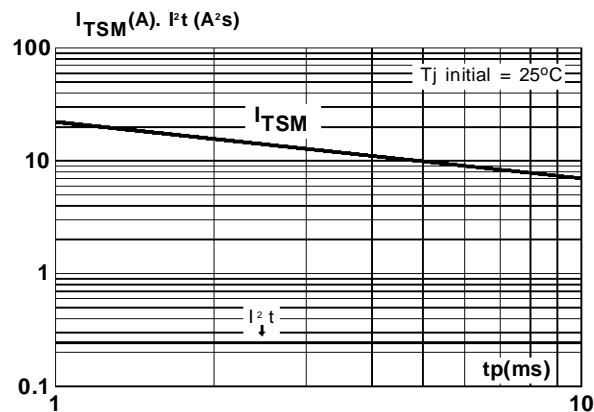
**Fig.6** : Non repetitive surge peak on-state current versus number of cycles.



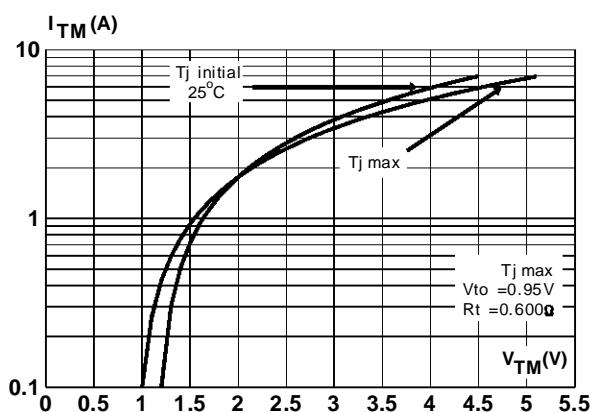
查询"P0102AA1AA3"供应商

P01xxxA/B

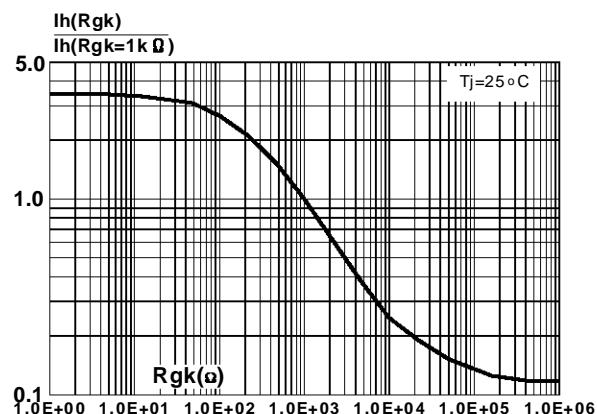
**Fig.7 :** Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $t_p \leq 10\text{ms}$ , and corresponding value of  $I^2t$ .



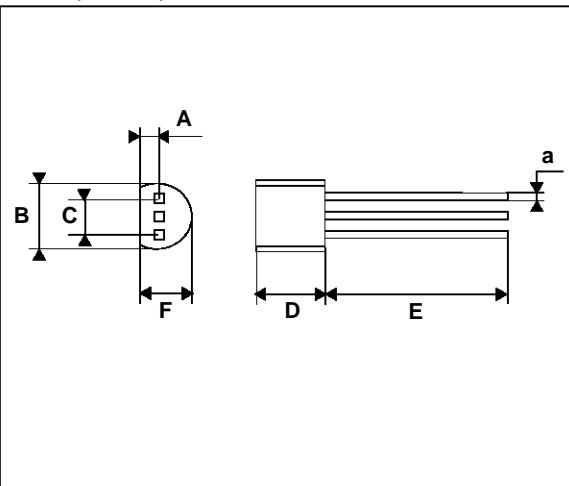
**Fig.8 :** On-state characteristics (maximum values).



**Fig.9 :** Relative variation of holding current versus gate-cathode resistance (typical values).



**PACKAGE MECHANICAL DATA**  
TO92 (Plastic)

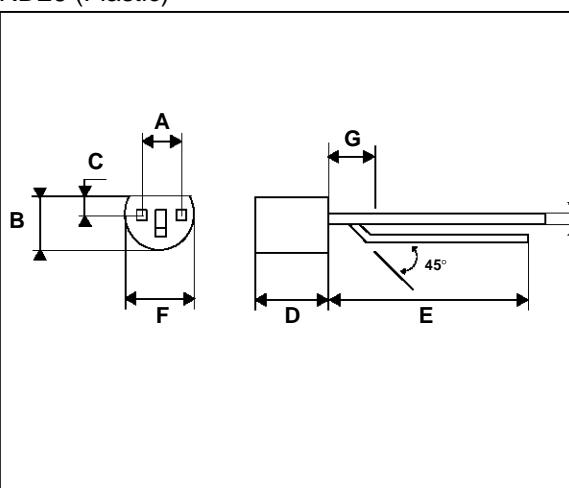


REF.	DIMENSIONS					
	Millimeters			Inches		
	Typ.	Min.	Max.	Typ.	Min.	Max.
A	1.35			0.053		
B			4.7			0.185
C	2.54			0.100		
D		4.4	4.8		0.173	0.189
E		12.7			0.500	
F			3.7			0.146
a			0.45			0.017

Marking : type number

Weight : 0.2 g

**PACKAGE MECHANICAL DATA**  
RD26 (Plastic)



REF.	DIMENSIONS					
	Millimeters			Inches		
	Typ.	Min.	Max.	Typ.	Min.	Max.
A	2.54			0.100		
B			3.7			0.146
C	1.35			0.053		
D		4.4	4.8		0.173	0.189
E		12.7			0.500	
F			4.7			0.185
G			3.0			0.118
a			0.45			0.177

Marking : type number

Weight : 0.2 g

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